Notice of Allowability	Application No.	Applicant(s)
	10/621,255	CHET ET AL.
	Examiner	Art Unit
	Nitin Parekh	2811
The MAILING DATE of this communication appeal All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RI	(OR REMAINS) CLOSED in this apport or other appropriate communication (GHTS. This application is subject to	plication. If not included will be mailed in due course. THIS
1. This communication is responsive to <u>01-12-05</u> .		
2. X The allowed claim(s) is/are <u>1-8,10-14 and 16-25</u> .		
 Acknowledgment is made of a claim for foreign priority una)	been received. been received in Application No	
Applicant has THREE MONTHS FROM THE "MAILING DATE" noted below. Failure to timely comply will result in ABANDONM THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.		complying with the requirements
4. A SUBSTITUTE OATH OR DECLARATION must be submi		
5. CORRECTED DRAWINGS (as "replacement sheets") mus	t be submitted.	
(a) ☐ including changes required by the Notice of Draftspers		948) attached
1) hereto or 2) to Paper No./Mail Date		
(b) including changes required by the attached Examiner's Paper No./Mail Date	s Amendment / Comment or in the C	Office action of
Identifying indicia such as the application number (see 37 CFR 1. each sheet. Replacement sheet(s) should be labeled as such in t		
6. DEPOSIT OF and/or INFORMATION about the deposit attached Examiner's comment regarding REQUIREMENT I		
Attachment(s) 1. ☑ Notice of References Cited (PTO-892)	5. ☐ Notice of Informal P	atent Application (PTO-152)
2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948)	6. ☐ Interview Summary	, ,
Information Disclosure Statements (PTO-1449 or PTO/SB/0 Paper No./Mail Date	Paper No./Mail Dat	e
4. ☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material	8. ☐ Examiner's Stateme	Ntin Parekh Primary Examiner Technology Center 2800

DETAILED ACTION

Allowable Subject Matter

1. Claims 1-8, 10-14 and 16-25 are allowed.

Examiner's Amendment

- 2. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.
- A. Claim 1, line 8: Delete "the substrate comprised of a dummy layer, a dielectric layer, and a solder mask structure, which encapsulates the dummy layer and the dielectric layer, the substrate mounted on the first surface, the substrate having an aperture where the aperture encompasses the integrated circuit die, and the substrate having and separating a plurality of conduction bands" and insert --- "mounted on the first surface, the substrate having an aperture where the aperture encompasses the integrated circuit die, and the substrate comprising a dummy layer, a dielectric layer, a solder mask structure and a plurality of separated conduction bands, wherein the solder mask structure and the plurality of conduction bands entirely encapsulate the dummy layer and the dielectric layer"---.

- B. Claim 18, line 10: Delete: "the substrate having and separating a plurality of conduction bands, and the substrate comprising a dummy layer, a dielectric layer, a solder mask structure which encapsulates the dummy layer and the dielectric layer" and insert --- "the substrate comprising a dummy layer, a dielectric layer, a solder mask structure and a plurality of separated conduction bands, wherein the solder mask structure and the plurality of conduction bands entirely encapsulate the dummy layer and the dielectric layer"---.
- C. Claim 25, line 10: Delete: "the substrate means having and separating a plurality of conduction means, and the substrate means comprising a dummy layer, a dielectric layer, a solder mask structure which encapsulates the dummy layer and the dielectric layer" and insert --- "the substrate means comprising a dummy layer, a dielectric layer, a solder mask structure and a plurality of separated conduction bands, wherein the solder mask structure and the plurality of conduction means entirely encapsulate the dummy layer and the dielectric layer"---.

Authorization for this examiner's amendment was given in a telephone interview with Kenneth Oplinger on 10-04-05.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Nitin Parekh whose telephone number is 571-272-1663. The examiner can normally be reached on 09:00AM-05:30PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's acting supervisor, Steven Loke can be reached on 571-272-1657. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAN or Public PAG. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAG system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). Any inquiry of a general nature or relating to the

status of this application or proceeding should be directed to the receptionist whose telephone number is 703-308-0956.

NP

NITIN PAREKH

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10-05-05

PRIMARY EXAMINER

TECHNOLOGY CENTER 2800